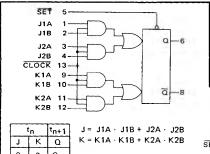
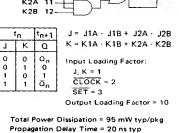
MC3100/MC3000 series

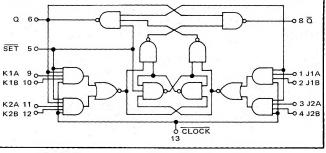
MC3154F • MC3054F MC3154L • MC3054L, P

"OR" INPUT
J-K FLIP-FLOP



This negative-edge clocked J-K Flip-Flop operates on the master-slave principle. AND-OR gate inputs enter data into the master section on the positive edge of the clock. This data is transferred to the slave section of the Flip-Flop on the negative edge of the clock. In order to assure entry of information into the Flip-Flop, data must not change after the positive edge of the clock.

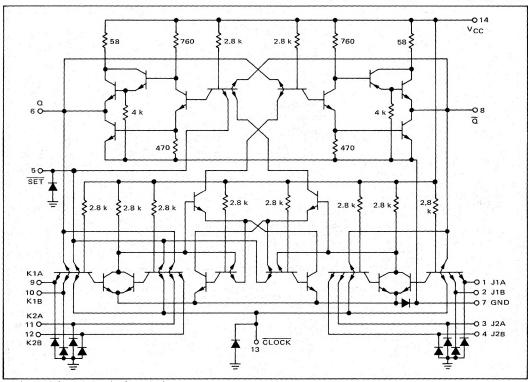




Pin numbers for the 54H71F/74H71F device are shown in the chart. These devices are available on special request.

Operating Frequency = 30 MHz typ

DEVICE						PIN	NU	MBE	RS					
MC3154F,L/3054F,L,P	1	2	3	4	5	6	7	8	9	10	11	12	13	14
54H71F/74H71F	5	6	7	8	9	10	11	12	1	2	13	14	3	4



See General Information section for packaging.

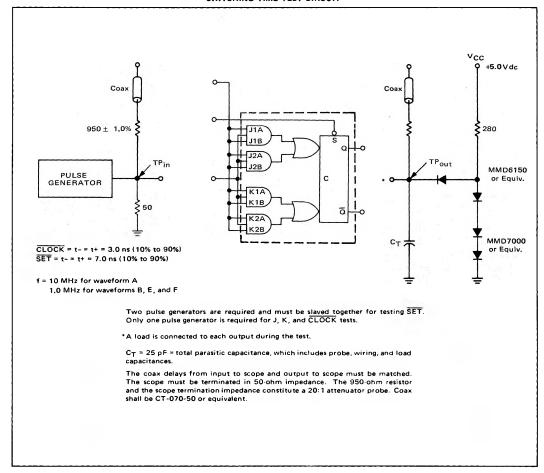
OPERATING CHARACTERISTICS

Data must be applied to the J-K inputs while the clock is low. When the clock input goes to the positive logic "1" state, the data at the J and K inputs is transferred to the master section, where it is stored until the clock changes to the positive logic "0" state. Data at the J and K inputs must not be changed while the clock is high. When the clock returns to the positive logic "0" state, information in the master section is transferred to the slave section.

Application of a logic "0" to the $\overline{\text{SET}}$ input will force the Q output to the logic "1" state. The $\overline{\text{SET}}$ input overrides the clock.

Since no charge storage is involved in this flip-flop, rise and fall times are not important to its operation. Clock fall times as long as 1.0 μ s will not adversely affect the operation of the flip-flop. The clock pulse need only be wide enough to allow the data to settle in the master section. This time, which is the setup time for a logic "1", is 12 ns minimum.

SWITCHING TIME TEST CIRCUIT



MC3154, MC3054 (continued)

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one	J and one K input on each AND gate, plus	the SET and CLOCK inputs. To complete	testing, sequence through remaining J and	K inputs in the same manner.

K14 K18	7 A B	5	4	10					-				TEST CUR	TEST CURRENT/VOLTAGE VALUES (All Temperatures)	All Temperatur	(sa.	7.			
25 25	K2A 11-	7	7					'		mA				Volts						
									<u>ا</u>	но	_ie	٧,	> a	V _{RH}	V _{IH}	V _{IL}	Vccı	V _{ССН}		
							2	MC3154	20	-1.5	1.0	0.4	2.4	4.5	2.0	0.8	4.5	5.5		
			N		.,1		2	MC3054	20	-1.5	1.0	0.4	2.4	4.5	2.0	0.8	4.75	5.25		
		Pin	MC3154 1 -55 to		Fest Limits +125°C		MC3054 Test Limits 0 to +75°C	Limits					EST CURREN	TEST CURRENT/VOLTAGE APPLIED TO PINS LISTED BELOW:	INS LISTED BE	LOW:				
Characteristic	Symbol	Test		Max	Unit	Min	Max	Unit	_ಠ	<u>Б</u>	_ <u>:</u> =	۸ ۲	>«	V _{RH}	> I	>	V _{CCL}	У ССН	* 4	Gnd
Input										4.5										
Forward Current J1A	I.			-2.0	mAdc	1	-2.0	mAdc		1		H:	ï	2,13	1		,	14		7,6
Set		25		-6.0		1.	-6.0					2		1,2,3,4,9,10,11,12,13	1 1					- [-
Clock		13 13	1. F	-4.0	-		-4.0	-	1 1	1 1	1 1	13	r i	1,2,3,4,5**,9,10,11,12	i i	1 1	ı dı	-	1 1	7,6
Leakage Current J1A	IBI	1	1	20	μAdc		50	дАфс	,			T.	1		-			14		2,5,7,13
KIA		11		150			150	_		10	111	, ,	11 .	1 1		1 1	, ,	_		5,6,7,12,13
Clock		13	r i	100	•	1.4	100	-	1, 1		1 1	11	22 23	1, 1	1, 1	1 1		-		1,2,3,4,5,7,9,10,11,12
J1A	BVin	1	5.5*		Vdc	5.5*		Vdc			1	1			1		-	14		2,5,7,13
KIA		1	7	1 1		- 5		-	, ,		1 5	1,1	•			1 1		_		6.7.9.10.11.12.13
Clock		13 23	•		•	•		•	1 4, 1		213	i i i			7			-		1,2,3,4,5,7,9,10,11,12
Output																	;			ī
Output Voltage	OF			0.4	Vac	r i	0.4	Vac	» •	1,1	į i				9,10,11,12	1,2,3,4	14	1 1	13	7,13
	МОЛ	98	2.4	1	Vdc Vdc	2.4		Vdc	1 1	9.8	1-1				9,10,11,12	1,2,3,4	14	11	13	7,13
Short-Circuit Current	$^{ m I}_{ m SC}$	9	-40	-100	mAdc	-40	-100	mAdc		1		1	1	1,2,3,4,9,10,11,12,13			1	14		5,6,7
		8	-40	-100	mAdc	-40	-100	mAdc	,	i			1.	1,2,3,4,5,9,10,11,12,13			1	14	1	6.7.8†
Power Requirements						1														
Power Supply Drain	. Qd	14 14	10	30	mAdc mAdc	i r	30	mAdc mAdc	. 1 1	- 1	1.6	1 1		1,2,3,4,5,9,10,11,12	11			14	: 1	1,2,3,4,5,7,9,10,11,12,13
0000																				

*Tested at 25°C only.

^{**}Momentarily ground pin prior to taking measurement, then apply 4.5 volts. $P_A = \sum_{i=1}^{4.5} V_i = V_i$

TEST PROCEDURES

(Letters shown in test columns refer to waveforms.)

TEAT	0,4400.		INPUT	_		ā		LIMITS	
TEST	SYMBOL	Č	J, K	Š	a	ď	Min	Max	Unit
Toggle Frequency	fTog	Α	2.4 V	2.4 V	†	†	25		MHz
Turn-On Delay	[†] pd-	В	В	2.4 V	С	С	-	27	ns
Turn-Off Delay	tpd+	В	В	2.4 V	D	D	-	21	ns
Turn-On Delay	tsd-	E	2.4 V	F	G	Н	-	24	ns
Turn-Off Delay	¹sd+	E	2.4 V	F	G	н	~	13	ns

[†]Output shall toggle with each input pulse.



